## Search Notes

10812936

HIEP NGUYEN

Applicant(s)/Patent Under Reexamination

BENDER, GRACE

Examiner

Art Unit

	SEARCHED			
Class		Subclass	Date	Examiner
705	02		9/11/2008	HN

SEARCH NOTES		
Search Notes	Date	Examiner
Searched EAST - See Attached Search History	9/11/2008	HN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/HIEP NGUYEN/ Examiner Art Unit 3626	

U.S. Patent and Trademark Office Part of Paper No.: 20080910